

# SEU WORKING GROUP

## GOALS

Define Level and Types of SEE Problems

Appropriate Mitigation

What's already done

needs Study

Provide Repository for Results

TWEPP 2010

# Mitigation of Single Event Effects

## SEE Domains

- ASIC Design → Today's topic
- FPGA Design → J. Christiansen announcement

Determine Mitigation requirements

Acceptable rates of

- Compromised of functional fidelity
- Loss of data integrity

What Level of mitigation is required?

Which ASIC Technology ?

# SEE sensitive Parameters to Understand / Study / Investigate

- Sensitive node spacing
- Relevant time frame (SEE lifetime)
- Supply sensitivity
- CC sensitive volume → Triple Well, T3, Substrate resistivity
- Enclosed Gate SEE advantages
- Power / Real estate / Development time costs of mitigation
- More??

**CAD friendly Approach** → Use Standard Digital Library parts  
DICE, TMR Time delay

- Device spacing
- Supply Sensitivity

→ Integrate custom part into Digital Library ??

→ Analog Approach for small special purpose blocks  
-- encoder / decoder counters pwr up reset etc.